



BN/SB/08A/B

Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Sheet 1 of 1

Complete If Known

Application Number	10/506,497
Filing Date	September 3, 2004
First Named Inventor	Einar NYGARD
Group Art Unit	
Examiner Name	
Attorney Docket Number	NYGARD=3

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
PL	AA	US-4,104,674	08-01-1978	LORENZE, Jr., et al	
PL	AB	US-4,547,792	10-15-1985	SCLAR	
PL	AC	US-4,857,748	08-15-1989	KUHLMANN et al	
PL	AD	US-5,254,868 A	10-19-1993	SAITO	
PL	AE	US-5,998,292 A	12-07-1999	BLACK et al	
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FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ³
		Country Code ⁴ Number ⁵ Kind Code ⁶ (if known)				
PL	AF	JP 61-128564 A2	06-16-1986	FUJITSU LTD.		Abs
PL	AG	EP 0 415 541 A1	03-06-1991	SHIMADZU CORPORATION		
PL	AH	EP 0 537 514 A2	04-21-1993	MITSUBISHI DENKI KABUSHIKI KAISHA		
PL	AI	EP 1 045 450 A2	10-18-2000	AGLENT TECHNOLOGIES INC.		

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²
PL	AJ	BENTHIEN, et al, "A Vertically Integrated High Resolution Active Pixel Image Sensor for Deep Submicron CMOS Processes", IEEE Workshop on CCDs and Advanced Image Sensors, Nagano, Japan, June 10-12, 1999.	

Examiner
Signature

/Patrick Lee/

Date
Considered

09/15/2006

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional). ² See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.